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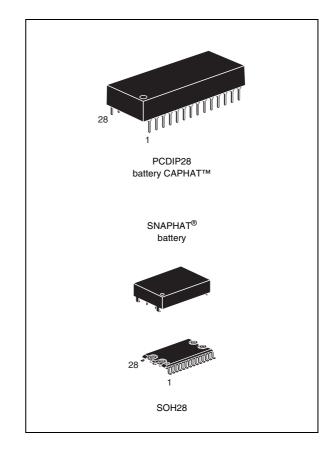


# M48Z58 M48Z58Y

# 5 V, 64 Kbit (8 Kbit x 8) ZEROPOWER<sup>®</sup> SRAM

### Features

- Integrated, ultra low power SRAM, power-fail control circuit, and battery
- READ cycle time equals WRITE cycle time
- Automatic power-fail chip deselect and WRITE protection
- WRITE protect voltages: (V<sub>PFD</sub> = power-fail deselect voltage)
  - M48Z58: V\_{CC} = 4.75 to 5.5 V; 4.5 V  $\leq$  V\_{PFD}  $\leq$  4.75 V
  - M48Z58Y:  $V_{CC}$  = 4.5 to 5.5 V; 4.2 V  $\leq V_{PFD} \leq$  4.5 V
- Self-contained battery in the CAPHAT<sup>™</sup> DIP package
- Packaging includes a 28-lead SOIC and SNAPHAT<sup>®</sup> top (to be ordered separately)
- SOIC package provides direct connection for a SNAPHAT<sup>®</sup> top which contains the battery
- Pin and function compatible with JEDEC standard 8 Kbit x 8 SRAMs
- RoHS compliant
  - Lead-free second level interconnect



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# 1 Description

The M48Z58/Y ZEROPOWER<sup>®</sup> RAM is an 8 Kbit x 8 non-volatile static RAM that integrates power-fail deselect circuitry and battery control logic on a single die. The monolithic chip is available in two special packages to provide a highly integrated battery-backed memory solution.

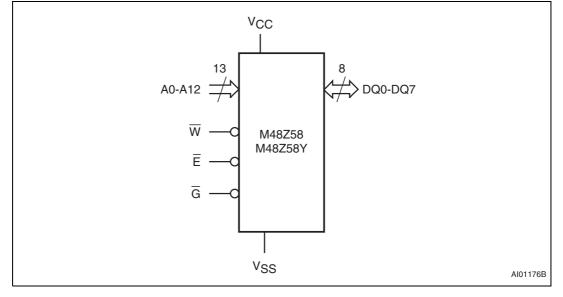
The M48Z58/Y is a non-volatile pin and function equivalent to any JEDEC standard 8 K x 8 SRAM. It also easily fits into many ROM, EPROM, and EEPROM sockets, providing the non-volatility of PROMs without any requirement for special WRITE timing or limitations on the number of WRITEs that can be performed.

The 28-pin, 600 mil DIP CAPHAT<sup>™</sup> houses the M48Z58/Y silicon with a long life lithium button cell in a single package.

The 28-pin, 330 mil SOIC provides sockets with gold plated contacts at both ends for direct connection to a separate SNAPHAT<sup>®</sup> housing containing the battery. The unique design allows the SNAPHAT battery package to be mounted on top of the SOIC package after the completion of the surface mount process. Insertion of the SNAPHAT housing after reflow prevents potential battery damage due to the high temperatures required for device surfacemounting. The SNAPHAT housing is keyed to prevent reverse insertion.

The SOIC and battery packages are shipped separately in plastic anti-static tubes or in tape & reel form.

For the 28-lead SOIC, the battery package (e.g., SNAPHAT) part number is "M4Z28-BR00SH1".



#### Figure 1. Logic diagram



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Table 1.	Signal names	
	A0-A12	Address inputs
	DQ0-DQ7	Data inputs / outputs
	Ē	Chip enable input
	G	Output enable input
	$\overline{W}$	WRITE enable input
	V <sub>CC</sub>	Supply voltage
	V <sub>SS</sub>	Ground
	NC	Not connected internally

Table 1. Signal names

#### Figure 2. DIP connections

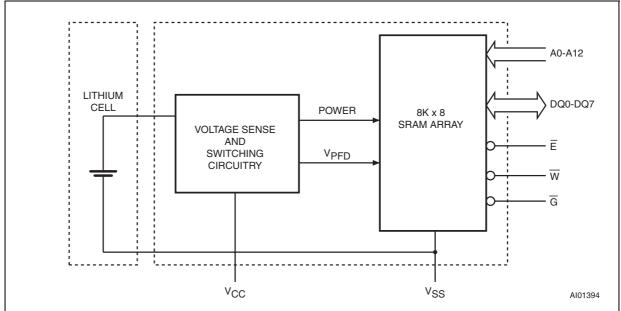
A12 [ 2 27 ] $\overline{W}$ A7 [ 3 26 ] NC A6 [ 4 25 ] A8 A5 [ 5 24 ] A9 A4 [ 6 23 ] A11 A3 [ 7 M48Z58 22 ] $\overline{G}$ A2 [ 8 M48Z58Y 21 ] A10 A1 [ 9 20 ] $\overline{E}$ A0 [ 10 19 ] DQ7 DQ0 [ 11 18 ] DQ6 DQ1 [ 12 17 ] DQ5 DQ2 [ 13 16 ] DQ4 VSS [ 14 15 ] DQ3		A7 [ 3 A6 [ 4 A5 [ 5 A4 [ 6 A3 [ 7 A2 [ 8 A1 [ 9 A0 [ 10 Q0 [ 11 Q0 [ 12 Q2 [ 13	M48Z58Y	26   NC 25   A8 24   A9 23   A11 22   G 21   A10 20   E 19   DQ7 18   DQ6 17   DQ5 16   DQ4		AI01177B	5
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#### Figure 3. SOIC connections

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#### Figure 4. Block diagram





# 2 Operating modes

The M48Z58/Y also has its own power-fail detect circuit. The control circuitry constantly monitors the single 5 V supply for an out of tolerance condition. When  $V_{CC}$  is out of tolerance, the circuit write protects the SRAM, providing a high degree of data security in the midst of unpredictable system operation brought on by low  $V_{CC}$ . As  $V_{CC}$  falls below battery switchover voltage ( $V_{SO}$ ), the control circuitry connects the battery which maintains data until valid power returns.

	- p - · · · · · · · · · · · · · · · · ·					
Mode	v <sub>cc</sub>	Е	G	w	DQ0-DQ7	Power
Deselect		V <sub>IH</sub>	Х	Х	High Z	Standby
WRITE	4.75 to 5.5 V or	V <sub>IL</sub>	Х	V <sub>IL</sub>	D <sub>IN</sub>	Active
READ	4.5 to 5.5 V	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	D <sub>OUT</sub>	Active
READ		V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	High Z	Active
Deselect	V <sub>SO</sub> to V <sub>PFD</sub> (min) <sup>(1)</sup>	Х	Х	Х	High Z	CMOS standby
Deselect	$\leq V_{SO}^{(1)}$	Х	Х	Х	High Z	Battery backup mode

#### Table 2. Operating modes

1. See *Table 10 on page 16* for details.

Note:

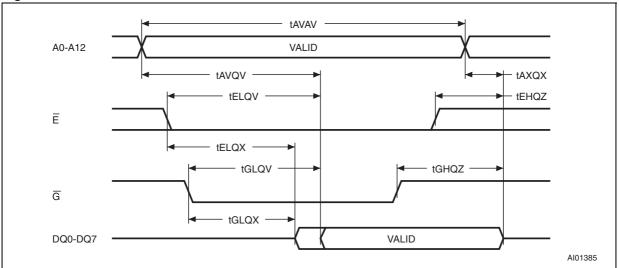
 $X = V_{IH}$  or  $V_{IL}$ ;  $V_{SO}$  = Battery backup switchover voltage.

### 2.1 READ mode

The M48Z58/Y is in the READ mode whenever  $\overline{W}$  (WRITE enable) is high,  $\overline{E}$  (chip enable) is low. Thus, the unique address specified by the 13 address inputs defines which one of the 8,192 bytes of data is to be accessed. Valid data will be available at the data I/O pins within address access time ( $t_{AVQV}$ ) after the last address input signal is stable, providing that the  $\overline{E}$  and  $\overline{G}$  access times are also satisfied. If the  $\overline{E}$  and  $\overline{G}$  access times are not met, valid data will be available after the latter of the chip enable access time ( $t_{ELQV}$ ) or output enable access time ( $t_{GLQV}$ ).

The state of the eight three-state data I/O signals is controlled by  $\overline{E}$  and  $\overline{G}$ . If the outputs are activated before  $t_{AVQV}$ , the data lines will be driven to an indeterminate state until  $t_{AVQV}$ . If the address inputs are changed while  $\overline{E}$  and  $\overline{G}$  remain active, output data will remain valid for output data hold time ( $t_{AXQX}$ ) but will go indeterminate until the next address access.





#### Figure 5. READ mode AC waveforms

Note: WRITE enable  $(\overline{W}) = High$ .

Symbol	Parameter <sup>(1)</sup>	M48Z	M48Z58/Y		
Symbol		Min	Max	– Unit	
t <sub>AVAV</sub>	READ cycle time	70		ns	
t <sub>AVQV</sub>	Address valid to output valid		70	ns	
t <sub>ELQV</sub>	Chip enable low to output valid		70	ns	
t <sub>GLQV</sub>	Output enable low to output valid		35	ns	
t <sub>ELQX</sub> <sup>(2)</sup>	Chip enable low to output transition	5		ns	
t <sub>GLQX</sub> <sup>(2)</sup>	Output enable low to output transition	5		ns	
t <sub>EHQZ</sub> <sup>(2)</sup>	Chip enable high to output Hi-Z		25	ns	
t <sub>GHQZ</sub> <sup>(2)</sup>	Output enable high to output Hi-Z		25	ns	
t <sub>AXQX</sub>	Address transition to output transition	10		ns	

1. Valid for ambient operating temperature:  $T_A = 0$  to 70 °C;  $V_{CC} = 4.75$  to 5.5 V or 4.5 to 5.5 V (except where noted).

2.  $C_L = 5 \text{ pF}$  (see *Figure 9 on page 14*).

### 2.2 WRITE mode

The M48Z58/Y is in the WRITE mode whenever  $\overline{W}$  and  $\overline{E}$  are low. The start of a WRITE is referenced from the latter occurring falling edge of  $\overline{W}$  or  $\overline{E}$ . A WRITE is terminated by the earlier rising edge of  $\overline{W}$  or  $\overline{E}$ . The addresses must be held valid throughout the cycle.  $\overline{E}$  or  $\overline{W}$  must return high for a minimum of t<sub>EHAX</sub> from chip enable or t<sub>WHAX</sub> from WRITE enable prior to the initiation of another READ or WRITE cycle. Data-in must be valid t<sub>DVWH</sub> prior to the end of WRITE and remain valid for t<sub>WHDX</sub> afterward.  $\overline{G}$  should be kept high during WRITE cycles to avoid bus contention; although, if the output bus has been activated by a low on  $\overline{E}$  and  $\overline{G}$ , a low on  $\overline{W}$  will disable the outputs t<sub>WLQZ</sub> after  $\overline{W}$  falls.



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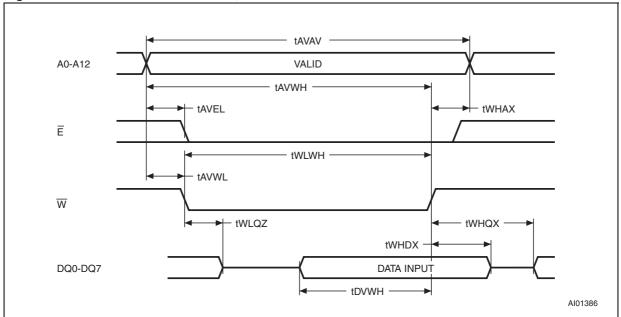
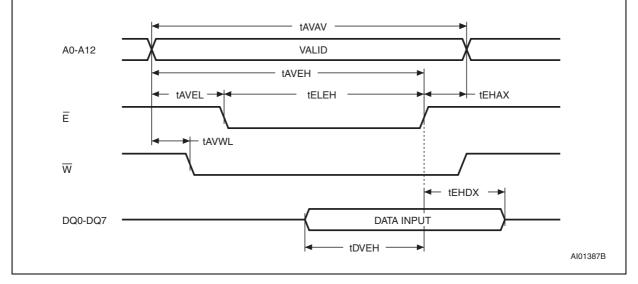


Figure 6. WRITE enable controlled, WRITE mode AC waveforms







_	- (1)	M482		
Symbol	Parameter <sup>(1)</sup>	Min	Max	Unit
t <sub>AVAV</sub>	WRITE cycle time	70		ns
t <sub>AVWL</sub>	Address valid to WRITE enable low	0		ns
t <sub>AVEL</sub>	Address valid to chip enable low	0		ns
t <sub>WLWH</sub>	WRITE enable pulse width	50		ns
t <sub>ELEH</sub>	Chip enable low to chip enable high	55		ns
t <sub>WHAX</sub>	WRITE enable high to address transition	0		ns
t <sub>EHAX</sub>	Chip enable high to address transition	0		ns
t <sub>DVWH</sub>	Input valid to WRITE enable high	30		ns
t <sub>DVEH</sub>	Input valid to chip enable high	30		ns
t <sub>WHDX</sub>	WRITE enable high to input transition	5		ns
t <sub>EHDX</sub>	Chip enable high to input transition	5		ns
t <sub>WLQZ</sub> <sup>(2)(3)</sup>	WRITE enable low to output Hi-Z		25	ns
t <sub>AVWH</sub>	Address valid to WRITE enable high	60		ns
t <sub>AVEH</sub>	Address valid to chip enable high	60		ns
t <sub>WHQX</sub> <sup>(2)(3)</sup>	WRITE enable high to output transition	5		ns

#### Table 4. WRITE mode AC characteristics

1. Valid for ambient operating temperature:  $T_A = 0$  to 70 °C;  $V_{CC} = 4.75$  to 5.5 V or 4.5 to 5.5 V (except where noted).

2.  $C_L = 5 \text{ pF}$  (see Figure 9 on page 14).

3. If  $\overline{E}$  goes low simultaneously with  $\overline{W}$  going low, the outputs remain in the high impedance state.

### 2.3 Data retention mode

With valid V<sub>CC</sub> applied, the M48Z58/Y operates as a conventional BYTEWIDE<sup>TM</sup> static RAM. Should the supply voltage decay, the RAM will automatically power-fail deselect, write protecting itself when V<sub>CC</sub> falls within the V<sub>PFD</sub> (max), V<sub>PFD</sub> (min) window. All outputs become high impedance, and all inputs are treated as "Don't care."

Note: A power failure during a WRITE cycle may corrupt data at the currently addressed location, but does not jeopardize the rest of the RAM's content. At voltages below  $V_{PFD}$  (min), the user can be assured the memory will be in a write protected state, provided the  $V_{CC}$  fall time is not less than  $t_F$  The M48Z58/Y may respond to transient noise spikes on  $V_{CC}$  that reach into the deselect window during the time the device is sampling  $V_{CC}$ . Therefore, decoupling of the power supply lines is recommended.

When V<sub>CC</sub> drops below V<sub>SO</sub>, the control circuit switches power to the internal battery which preserves data. The internal button cell will maintain data in the M48Z58/Y for an accumulated period of at least 10 years when V<sub>CC</sub> is less than V<sub>SO</sub>.

As system power returns and V<sub>CC</sub> rises above V<sub>SO</sub>, the battery is disconnected, and the power supply is switched to external V<sub>CC</sub>. Normal RAM operation can resume t<sub>rec</sub> after V<sub>CC</sub> exceeds V<sub>PFD</sub> (max).

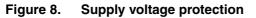
For more information on battery storage life refer to the application note AN1012.

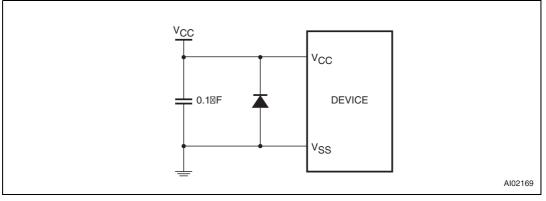


### 2.4 V<sub>CC</sub> noise and negative going transients

 $I_{CC}$  transients, including those produced by output switching, can produce voltage fluctuations, resulting in spikes on the  $V_{CC}$  bus. These transients can be reduced if capacitors are used to store energy which stabilizes the  $V_{CC}$  bus. The energy stored in the bypass capacitors will be released as low going spikes are generated or energy will be absorbed when overshoots occur. A ceramic bypass capacitor value of 0.1  $\mu$ F (see *Figure 8*) is recommended in order to provide the needed filtering.

In addition to transients that are caused by normal SRAM operation, power cycling can generate negative voltage spikes on V<sub>CC</sub> that drive it to values below V<sub>SS</sub> by as much as one volt. These negative spikes can cause data corruption in the SRAM while in battery backup mode. To protect from these voltage spikes, ST recommends connecting a schottky diode from V<sub>CC</sub> to V<sub>SS</sub> (cathode connected to V<sub>CC</sub>, anode to V<sub>SS</sub>). (Schottky diode 1N5817 is recommended for through hole and MBRS120T3 is recommended for surface mount).







# 3 Maximum ratings

Stressing the device above the rating listed in the absolute maximum ratings table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Symbol	Parameter	Value	Unit	
Τ <sub>Α</sub>	Ambient operating temperature		0 to 70	°C
		SNAPHAT <sup>®</sup> top	-40 to 85	°C
T <sub>STG</sub>	Storage temperature (V <sub>CC</sub> off, oscillator off)	CAPHAT <sup>®</sup> DIP	-40 to 85	°C
	SOH28	-55 to 125	°C	
T <sub>SLD</sub> <sup>(1)(2)</sup>	Lead solder temperature for 10 seconds		260	°C
V <sub>IO</sub>	Input or output voltages	Input or output voltages		
V <sub>CC</sub>	Supply voltage	-0.3 to 7.0	V	
Ι <sub>Ο</sub>	Output current	20	mA	
PD	Power dissipation		1	W

Table 5.	Absolute	maximum	ratings
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 For DIP package, soldering temperature of the IC leads is to not exceed 260 °C for 10 seconds. Furthermore, the devices shall not be exposed to IR reflow nor preheat cycles (as performed as part of wave soldering). ST recommends the devices be hand-soldered or placed in sockets to avoid heat damage to the batteries.

 For SOH28 package, lead-free (Pb-free) lead finish: reflow at peak temperature of 260 °C (the time above 255 °C must not exceed 30 seconds).

*Caution:* Negative undershoots below –0.3 V are not allowed on any pin while in the battery backup mode.

*Caution:* Do NOT wave solder SOIC to avoid damaging SNAPHAT<sup>®</sup> sockets.



# 4 DC and AC parameters

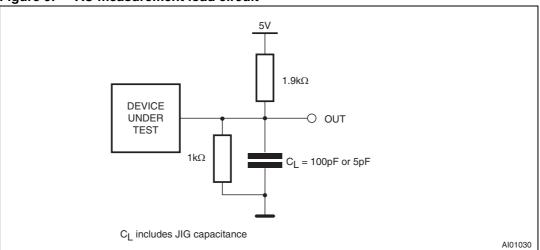
This section summarizes the operating and measurement conditions, as well as the DC and AC characteristics of the device. The parameters in the following DC and AC characteristic tables are derived from tests performed under the measurement conditions listed in *Table 6: Operating and AC measurement conditions*. Designers should check that the operating conditions in their projects match the measurement conditions when using the quoted parameters.

Parameter	M48Z58	M48Z58Y	Unit				
Supply voltage (V <sub>CC</sub> )	4.75 to 5.5	4.5 to 5.5	V				
Ambient operating temperature (T <sub>A</sub> )	0 to 70	0 to 70	°C				
Load capacitance (CL)	100	100	pF				
Input rise and fall times	≤ 5	≤ 5	ns				
Input pulse voltages	0 to 3	0 to 3	V				
Input and output timing ref. voltages	1.5	1.5	V				

 Table 6.
 Operating and AC measurement conditions

Note:

### Output Hi-Z is defined as the point where data is no longer driven.



#### Figure 9. AC measurement load circuit

#### Table 7. Capacitance

Symbol	Parameter <sup>(1)(2)</sup>	Min	Мах	Unit
C <sub>IN</sub>	Input capacitance	-	10	pF
C <sub>IO</sub> <sup>(3)</sup>	Input / output capacitance	-	10	pF

1. Effective capacitance measured with power supply at 5 V. Sampled only, not 100% tested.

2. At 25 °C, f = 1 MHz.

3. Outputs deselected.



Symbol	Parameter Test condition <sup>(1)</sup>		Min	Max	Unit
I <sub>LI</sub>	Input leakage current	$0 \text{ V} \leq \text{V}_{\text{IN}} \leq \text{V}_{\text{CC}}$		±1	μA
I <sub>LO</sub> <sup>(2)</sup>	Output leakage current	$0 V \le V_{OUT} \le V_{CC}$		±1	μA
I <sub>CC</sub>	Supply current	Outputs open		50	mA
I <sub>CC1</sub>	Supply current (standby) TTL	$\overline{E} = V_{IH}$		3	mA
I <sub>CC2</sub>	Supply current (standby) CMOS	$\overline{E} = V_{CC} - 0.2 V$		3	mA
V <sub>IL</sub>	Input low voltage		-0.3	0.8	V
V <sub>IH</sub>	Input high voltage		2.2	V <sub>CC</sub> + 0.3	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -1 mA	2.4		V

#### Table 8.DC characteristics

1. Valid for ambient operating temperature:  $T_A = 0$  to 70 °C;  $V_{CC} = 4.75$  to 5.5 V or 4.5 to 5.5 V (except where noted).

2. Outputs deselected.

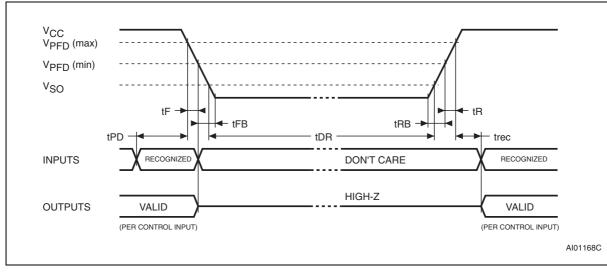


Figure 10. Power down/up mode AC waveforms



Symbol	Parameter <sup>(1)</sup>	Min	Мах	Unit
t <sub>PD</sub>	$\overline{E}$ or $\overline{W}$ at $V_{IH}$ before power down	0		μs
t <sub>F</sub> <sup>(2)</sup>	$V_{PFD}$ (max) to $V_{PFD}$ (min) $V_{CC}$ fall time	300		μs
t <sub>FB</sub> <sup>(3)</sup>	$V_{\text{PFD}}$ (min) to $V_{\text{SS}}$ $V_{\text{CC}}$ fall time	10		μs
t <sub>R</sub>	$V_{\text{PFD}}$ (min) to $V_{\text{PFD}}$ (max) $V_{\text{CC}}$ rise time	10		μs
t <sub>RB</sub>	$V_{SS}$ to $V_{PFD}$ (min) $V_{CC}$ rise time	1		μs
t <sub>rec</sub>	V <sub>PFD</sub> (max) to inputs recognized	40	200	ms

Table 9. Power down/up AC characteristics

1. Valid for ambient operating temperature:  $T_A = 0$  to 70 °C;  $V_{CC} = 4.75$  to 5.5 V or 4.5 to 5.5 V (except where noted).

2.  $V_{PFD}$  (max) to  $V_{PFD}$  (min) fall time of less than  $t_F$  may result in deselection/write protection not occurring until 200 µs after  $V_{CC}$  passes  $V_{PFD}$  (min).

3.  $V_{PFD}$  (min) to  $V_{SS}$  fall time of less than  $t_{FB}$  may cause corruption of RAM data.

Symbol	Parameter <sup>(1)(2)</sup>	Min	Тур	Max	Unit	
V	V <sub>PFD</sub> Power-fail deselect voltage	M48Z58	4.5	4.6	4.75	V
♥ PFD		M48Z58Y	4.2	4.35	4.5	V
V <sub>SO</sub>	Battery backup switchover vo		3.0		V	
t <sub>DR</sub> <sup>(3)</sup>	Expected data retention time		10			Years

1. All voltages referenced to  $V_{SS}$ .

2. Valid for ambient operating temperature:  $T_A = 0$  to 70 °C;  $V_{CC} = 4.75$  to 5.5 V or 4.5 to 5.5 V (except where noted).

3. At 25 °C,  $V_{CC} = 0 V$ .

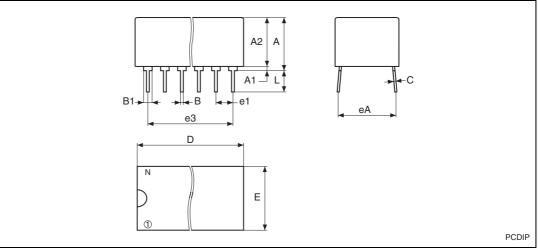


# 5 Package mechanical data

Drawing is not to scale.

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.

Figure 11. PCDIP28 – 28-pin plastic DIP, battery CAPHAT™, package outline



#### Note:

Table 11 PCDIP28 – 28-nin plastic DIP battery CAPHAT™ pack mech data

Table 11.	PCDIP28 – 28-pin plastic DIP, battery CAPHAT™, pack. mech. data						
Symbol		mm		inches			
Symbol	Тур	Min	Max	Тур	Min	Max	
Α		8.89	9.65		0.350	0.380	
A1		0.38	0.76		0.015	0.030	
A2		8.38	8.89		0.330	0.350	
В		0.38	0.53		0.015	0.021	
B1		1.14	1.78		0.045	0.070	
С		0.20	0.31		0.008	0.012	
D		39.37	39.88		1.550	1.570	
Е		17.83	18.34		0.702	0.722	
e1		2.29	2.79		0.090	0.110	
e3	33.02			1.3			
eA		15.24	16.00		0.600	0.630	
L		3.05	3.81		0.120	0.150	
Ν		28	•		28		

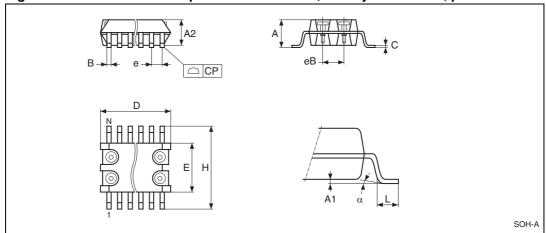


Figure 12. SOH28 – 28-lead plastic small outline, battery SNAPHAT<sup>®</sup>, pack. outline

Note: Drawing is not to scale.

	data						
Symbol		mm			inches	es	
Symbol	Тур	Min	Max	Тур	Min	Max	
А			3.05			0.120	
A1		0.05	0.36		0.002	0.014	
A2		2.34	2.69		0.092	0.106	
В		0.36	0.51		0.014	0.020	
С		0.15	0.32		0.006	0.012	
D		17.71	18.49		0.697	0.728	
Е		8.23	8.89		0.324	0.350	
е	1.27	-	-	0.050	-	-	
eB		3.20	3.61		0.126	0.142	
Н		11.51	12.70		0.453	0.500	
L		0.41	1.27		0.016	0.050	
а		0°	8°		0°	8°	
Ν		28	•		28		
CP			0.10			0.004	

 Table 12.
 SOH28 – 28-lead plastic small outline, battery SNAPHAT<sup>®</sup>, pack. mech. data



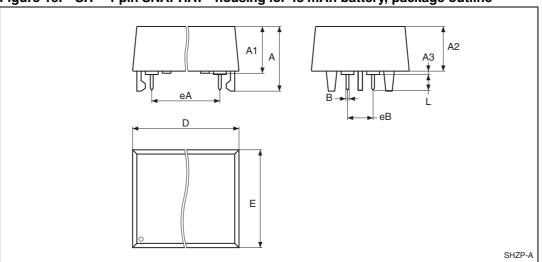


Figure 13. SH – 4-pin SNAPHAT<sup>®</sup> housing for 48 mAh battery, package outline

Note: Drawing is not to scale.

Table 13.	SH – 4-pin SNAPHAT <sup>®</sup> housing for 48 mAh battery, package mech. data
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Symbol	Symbol		mm			inches	
Symbol	Тур	Min	Max	Тур	Min	Max	
А			9.78			0.385	
A1		6.73	7.24		0.265	0.285	
A2		6.48	6.99		0.255	0.275	
A3			0.38			0.015	
В		0.46	0.56		0.018	0.022	
D		21.21	21.84		0.835	0.860	
E		14.22	14.99		0.560	0.590	
eA		15.55	15.95		0.612	0.628	
eB		3.20	3.61		0.126	0.142	
L		2.03	2.29		0.080	0.090	



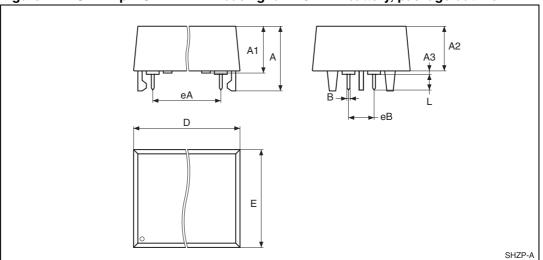


Figure 14. SH – 4-pin SNAPHAT<sup>®</sup> housing for 120 mAh battery, package outline

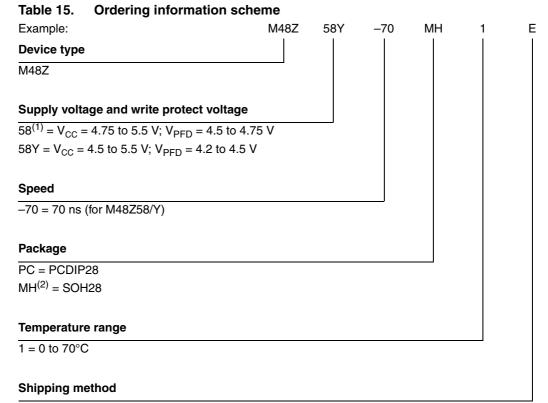
Note: Drawing is not to scale.

Table 14.	SH – 4-pin SNAPHAT <sup>®</sup>	housing for 120 mAh	battery, pack. mech. data

Cumh	Symb		mm		inches	
Symp	Тур	Min	Max	Тур	Min	Мах
А			10.54			0.415
A1		8.00	8.51		0.315	0.335
A2		7.24	8.00		0.285	0.315
A3			0.38			0.015
В		0.46	0.56		0.018	0.022
D		21.21	21.84		0.835	0.860
E		17.27	18.03		0.680	0.710
eA		15.55	15.95		0.612	0.628
eB		3.20	3.61		0.126	0.142
L		2.03	2.29		0.080	0.090



# 6 Part numbering



For SOH28:

 $E = ECOPACK^{\mathbb{R}}$  package, tubes

F = ECOPACK<sup>®</sup> package, tape & reel

For PCDIP28:

blank = ECOPACK<sup>®</sup> package, tubes

- 1. The M48Z58 part is offered with the PCDIP28 (ie., CAPHAT™) package only.
- The SOIC package (SOH28) requires the SNAPHAT<sup>®</sup> battery package which is ordered separately under the part number "M4Zxx-BR00SH1" in plastic tubes (see *Table 16*).
- **Caution:** Do not place the SNAPHAT<sup>®</sup> battery package "M4Zxx-BR00SH1" in conductive foam as it will drain the lithium button-cell battery.

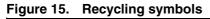
For other options, or for more information on any aspect of this device, please contact the ST sales office nearest you.

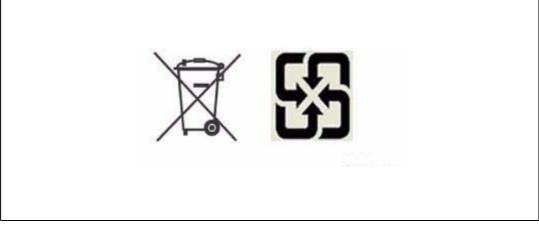
#### Table 16. SNAPHAT<sup>®</sup> battery table

Part number	Description	Package
M4Z28-BR00SH1	Lithium battery (48 mAh) SNAPHAT®	SH
M4Z32-BR00SH1	Lithium battery (120 mAh) SNAPHAT®	SH



# 7 Environmental information





This product contains a non-rechargeable lithium (lithium carbon monofluoride chemistry) button cell battery fully encapsulated in the final product.

Recycle or dispose of batteries in accordance with the battery manufacturer's instructions and local/national disposal and recycling regulations.



# 8 Revision history

Table 17.	Document revision history
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Date	Revision	Changes
March 1999	1	First issue
10-Feb-2000	1.1	2-socket SOH and 2-pin SH packages removed
22-Feb-2000	1.2	Data retention mode paragraph changed
14-Sep-2001	2	Reformatted; added temperature information (Table 7, 8, 3, 4, 9, 10)
29-May-2002	2.1	Modify reflow time and temperature footnotes (Table 5)
16-Sep-2002	2.2	Remove footnote from ordering information (Table 15)
02-Apr-2003	3	v2.2 template applied; test condition updated (Table 10)
23-Mar-2004	4	Reformatted; updated lead-free information (Table 5, 15)
23-Nov-2004	5	Remove references to industrial temperature grade ( <i>Table 3, 4, 5, 6, 8, 9, 10, 15</i> )
09-Jun-2005	6	Removal of SNAPHAT <sup>®</sup> , industrial temperature sales types ( <i>Table 3</i> , 4, 5, 6, 7, 8, 10, 15)
14-Dec-2005	7	Updated lead-free text (Table 15)
06-Nov-2007	8	Reformatted; added lead-free second level interconnect information to cover page and <i>Section 5: Package mechanical data</i> ; updated <i>Table 5</i> , <i>15</i> , <i>16</i> .
10-Mar-2009	9	Updated <i>Table 5</i> , text in <i>Section 5: Package mechanical data</i> ; added <i>Section 7: Environmental information</i> ; minor reformatting.
14-Oct-2010	10	Updated Section 3, Table 11; reformatted document.
07-Jun-2011	11	Updated footnote 1 of <i>Table 5: Absolute maximum ratings</i> ; updated <i>Section 7: Environmental information</i> .



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